

# AEC-Q100

## Reliability Test Report

QR-TC-18

**Name of Client:** Shanghai Fudan Microelectronics Group Co., Ltd  
**Address of Client:** Building 4, 127 Guotai Road Shanghai 200433, China  
**Sample Name:** FM33LE025A/FM33LE015A  
**Sample Information:** Test Group A/C: C5B30NFG/C5B34NCG/C5B36N0G  
Test Group B/E: C5B30NEG/C5B34NAG/C5B36N9G  
**Date of Receipt:** 2022/10/26  
**Test Method:** AEC Q100-Rev-H-2014 Grade 1: -40°C ~ +125°C  
**Test Period:** 2022/10/27 ~ 2023/01/10  
**Test Result:**

This is to certify that the above-mentioned product(s) complies with the standard & technical requirements of "AEC-Q100-Rev-H: 2014 Failure mechanism-based stress test qualification for integrated circuits". The assessment has been completed under the AEC-Q100 Grade 1, which meet the demands of the above technical standards and product specifications. The sample is qualified for this test. For further details, please refer to Test Result Summary.

**Prepared by** Chen Chao

**Checked by** Xu Yongjun

**Authorized by** Ma XiChun

(signature) Chen Chao

(signature) Xu Yongjun

(signature) Ma XiChun

Wuxi CMC electronics Co., Ltd

Issued Date: 2023/01/13

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